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(54) Title of the invention : AN INTEGRATED BIOMETRIC MACHINE LEARNING DEVICE TO MEASURE EMPLOYEE STRESS, ANXIETY AND BURNOUT

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Application No Filing Date	:PCT// :01/01/1900	Name of Applicant : NA Address of Applicant : NA
(87) International Publication No	: NA	(72)Name of Inventor :1)Ms. Ekata Deb
(61) Patent of Additio to Application Numbe Filing Date	n:NA or:NA	Address of Applicant :Student of Law Department, Brainware University, 398, Ramkrishnapur Rd, near Jagadighata Market, Barasat, Kolkata, West Bengal 700125
(62) Divisional to Application Number Filing Date	:NA :NA	2)Dr. Shivnath Ghosh Address of Applicant :Associate Professor, Dept. of CSE, Brainware University, 398, Ramkrishnapur Rd, near Jagadighata Market, Barasat, Kolkata, West Bengal 700125

(57) Abstract :

[029] The present invention relates to the field of an integrated biometric machine learning device. The invention more particularly relates to measure three behavioural constructs stress, anxiety and burnt- out using an in-built model having developed a predictive AI enabled biometric device for the employees of an organization. The invention check out for the prevalence and bi-weekly workplace mental health report of the employees by measuring stress, anxiety and burnt-out using an inbuilt facial emotion recognition model, ocular response measurement and skin scanning mechanism to measure BP and pulse. The device develops intelligent coding system using CNN Model and SVM model of machine learning. Accompanied Drawing [FIG. 1]

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